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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/503,608	ATTWOOD ET AL.	
Examiner	Art Unit	
Ellen C. Tran	2134	

SEARCHED			
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726	22	10/10/2006	ECT
726	23	10/10/2006	ECT
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INTERFERENCE SEARCHED			
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USPTO, USPG, EPO, JPO, OCR, DERWENT, IBM TECH DES	10/10/2006	ECT
NPL - IEEE XPLORE	10/10/2006	ECT
All claims have been reviewed for possible 101 rejections	10/10/2006	ECT
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09/503,608	ATTWOOD ET AL.	
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Application No.	Applicant(s)
09/503,608	ATTWOOD ET AL.
Examiner	Art Unit
Ellen C Tran	2134

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713	201	3/30/2005	ECT				
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